

**Notice of References Cited**

Application/Control No.

10/057,086

Applicant(s)/Patent Under  
Reexamination  
ASHTON ET AL.

Examiner

Jong-Suk (James) Lee

Art Unit

3673

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,363,681	04-2002	Neuner, John D.	52/736.1
	B	US-6,135,675	10-2000	Moreau, Jeffrey M.	405/284
	C	US-5,542,229	08-1996	Saito et al.	52/731.2
	D	US-5,218,810	06-1993	Isley, Jr., Frederick P.	52/736.3
	E	US-5,175,973	01-1993	Owen et al.	405/216
	F	US-5,043,033	08-1991	Fyfe, Edward R.	405/216
	G	US-4,786,341	11-1988	Kobatake et al.	52/721.4
	H	US-4,694,622	09-1987	Richard, Pierre	52/223.5
	I	US-2,677,165	05-1954	Copenhaver et al.	405/257
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	173446 6	03-1986	EPO	Riley	405/211
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.